

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1724	SERIAL NO. 09/905,286	
LIST OF ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT Cem Basceri et al.		
				FILING DATE July 13, 2001		
U.S. PATENT DOCUMENTS						
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
EF	AA	5,834,060	11/1998	Kawahara et al.	427/	255.3
EF	AB	6,126,753	10/2000	Shinriki et al.	118/	715
EF	AC	6,245,652	06/2001	Gardner et al.	438/	592
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FOREIGN PATENT DOCUMENTS						
	Document Number	Date	Country	Class	Subclass	Translation
						Yes No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
EF	AR		Basceri, et al., "The dielectric response as a function of temperature and film thickness of fiber-textured (Ba,Sr) TiO ₂ thin films grown by chemical vapor deposition", Journal of Appl. Phys. 82 (5), 09/01/97.			
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EXAMINER			DATE CONSIDERED			
C. F. F.			4/14/02			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>						

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EF	AA	09/652,907	Basceri, et al.			08/31/2000
EF	AB	09/776,217	Basceri			02/02/2001
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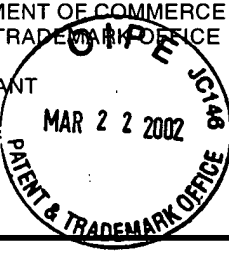
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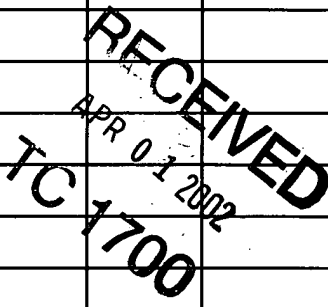
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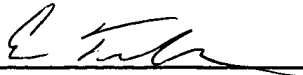


U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
BF	AA	5,596,214	01/1997	Endo	257/	324	
EP	AB						
	AC	09/388,063		Agerwal et al. (As filed, and amended in response to 06/20/01 Office Action; 12/20/00 Office Action; and 11/29/01 Office Action.)		August 30, 1999	
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DATE CONSIDERED *4/19/02*

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EF	AR		DISSERTATION: Cem Basceri, <i>Electrical and Dielectric Properties of (Ba,Sr)TiO₃ Thin Film CAPACITORY FOR ULTRA-HIGH DENISITY</i> , 171 pages (North Carolina State University 1997).
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